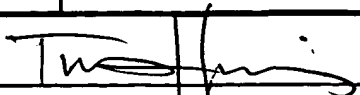
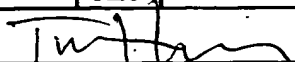
 <p>INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)</p>				Docket Number (Optional) 27470 USA		Application Number 10/733,048		
				Applicant(s) Hirofumi OKADA				
				Filing Date December 10, 2003		Group Art Unit		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TRH	AA	6,275,141	08/14/2001	Walter	340	5.64		
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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
TRH	AC	WO 01/20110	03/22/2001	PCT (abstract only in Eng)				✓
TRH	AD	EP 0987389	03/22/2000	EPO (abstract only in Eng.)				✓
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
	AE	European Search Report, dated March 4, 2004, issued in corresponding European Application No. 03028520						
EXAMINER 				DATE CONSIDERED 4/11/2005				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449 Modified List of Patents and Publications Cited by Applicant (Use several sheets if necessary) U.S. Department of Commerce Patent and Trademark Office		Docket No. 27,470 USA		Application No. As yet unassigned 10/733048		
		Applicant(s) Hirofumi Okada				
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Examiner 		Date Considered 4/4/2005				

* Abstract only available in English